

Description

The AP3416AI uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 20V I_{D} = 6.8A$

 $R_{DS(ON)}$ < 22m Ω @ V_{GS} =4.5V (Type:15m Ω)

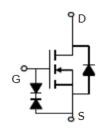
ESD≥2500HBM

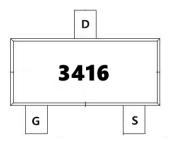
Application

Lithium battery protection

Wireless impact

Mobile phone fast charging







Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|--------|---------|----------|
| AP3416A | SOT23L | 3416 | 3000 |

Absolute Maximum Ratings (T_C=25°Cunless otherwise noted)

| Symbol | Parameter | Rating | Units |
|--------------------------------------|--|------------|-------|
| V _{DS} | Drain-Source Voltage | 20 | V |
| Vgs | Gate-Source Voltage | ±12 | V |
| I _D @T _A =25°C | Continuous Drain Current | 6.8 | Α |
| I _D @T _A =70°C | Continuous Drain Current | 6.0 | А |
| Ірм | Pulsed Drain Current ² | 30 | А |
| P _D @T _A =25°C | Total Power Dissipation ³ | 1.5 | W |
| Тѕтс | Storage Temperature Range | -55 to 150 | °C |
| TJ | Operating Junction Temperature Range | -55 to 150 | °C |
| $R_{	heta JA}$ | Thermal Resistance Junction-ambient ¹ | 125 | °C/W |





Electrical Characteristics (Tc=25°Cunless otherwise noted)

| Symbol | Parameter | Conditions | Min | Тур | Max | Units |
|-----------------|-----------------------------------|--|------|------|------|-------|
| BVDSS | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =250µA | 20 | 22 | | V |
| VGS(th) | Gate Threshold Voltage | V _{DS} = V _{GS} , I _D =250µA | 0.50 | 0.65 | 1.0 | V |
| RDS(ON) | Static Drain-Source On-Resistance | V _{GS} =4.5V, I _D =4A | | 15 | 22 | 0 |
| RDS(ON) | Static Drain-Source On-Resistance | V _{GS} =2.5V, I _D =3A | | 20 | 30 | mΩ |
| IDSS | Zero Gate Voltage Drain Current | V _{DS} =20V,V _{GS} =0V | | | 1 | μA |
| IGSS | Gate-Body Leakage Current | V _{GS} =±10V, V _{DS} =0V | | | ±100 | nA |
| Ciss | Input Capacitance | | | 780 | | |
| Coss | Output Capacitance | V _{DS} =10V,V _{GS} =0V,f=1MHZ | | 140 | | pF |
| Crss | Reverse Transfer Capacitance | | | 80 | | |
| Qg | Total Gate Charge | | | 11 | | |
| Q _{gs} | Gate-Source Charge | V _{GS} =4.5V,V _{DS} =10V,I _D =6.8A | | 2.3 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 2.9 | | |
| tD(on) | Turn-on Delay Time | | | 9 | | |
| t _r | Turn-on Rise Time | V _{GS} =4.5V, V _{DS} =10V, I _D =6.8A | | 30 | | ns |
| tD(off) | Turn-off Delay Time | R _{GEN} =3Ω | | 35 | | 113 |
| t _f | Turn-off fall Time | | | 10 | | |
| V _{SD} | Diode Forward Voltage | I _S =6.8A,V _{GS} =0V | | | 1.2 | V |

Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width $\leqq 300 us$, duty cycle $\leqq 2\%$
- $3 {\,{}^{^{\circ}}}$ The power dissipation is limited by $150 {\,{}^{\circ}\!{}^{^{\circ}}}$ junction temperature
- 4. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation



Typical Characteristics

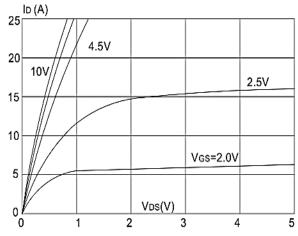
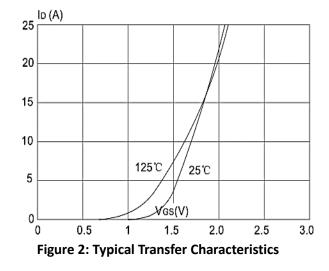


Figure1: Output Characteristics



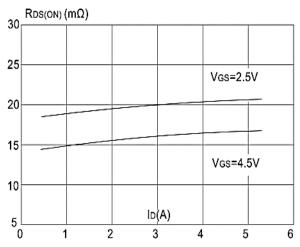


Figure 3:On-resistance vs. Drain Current

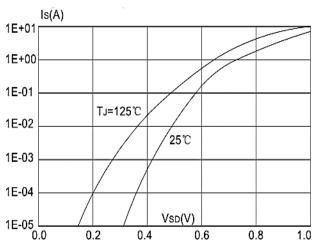


Figure 4: Body Diode Characteristics

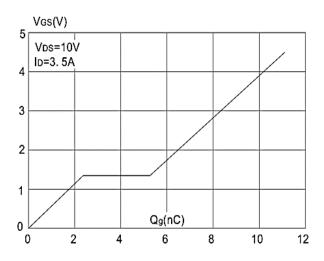


Figure 5: Gate Charge Characteristics

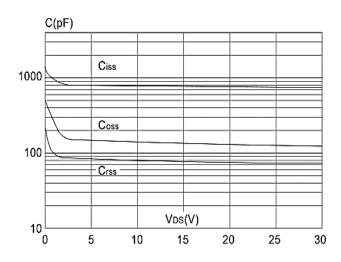


Figure 6: Capacitance Characteristics





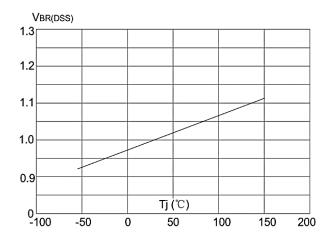


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

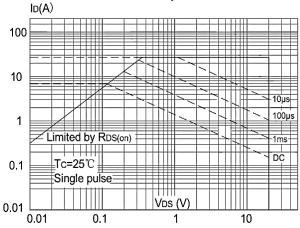


Figure 9: Maximum Safe Operating Area vs. Case Temperature

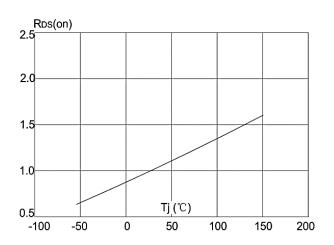


Figure 8: Normalized on Resistance vs Junction Temperature

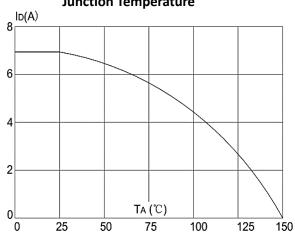


Figure 10: Maximum Continuous Drain Current

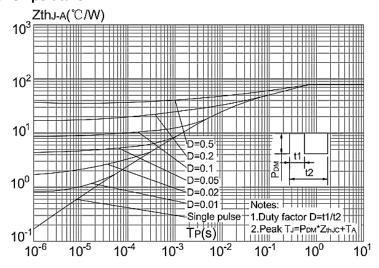
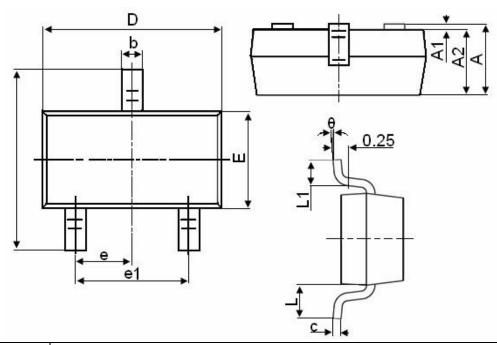


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



Package Mechanical Data-SOT23-XC-Single



| Cumah al | Dimensions in Millimeters | | |
|----------|---------------------------|-------|--|
| Symbol | MIN. | MAX. | |
| Α | 0.900 | 1.150 | |
| A1 | 0.000 | 0.100 | |
| A2 | 0.900 | 1.050 | |
| b | 0.300 | 0.500 | |
| С | 0.080 | 0.150 | |
| D | 2.800 | 3.000 | |
| Е | 1.200 | 1.400 | |
| E1 | 2.250 | 2.550 | |
| е | 0.950TYP | | |
| e1 | 1.800 | 2.000 | |
| L | 0.550REF | | |
| L1 | 0.300 | 0.500 | |
| θ | 0° | 8° | |



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| Edition | Date | Change |
|---------|-----------|-----------------|
| Rve1.0 | 2020/9/11 | Initial release |

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